

# CSE435 Introduction to EDA & Testing - Spring 2022

## Homework Assignment #5

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1. (20%) A circuit has the truth table of Table 1. When there is a fault (faults) on the circuit, the faulty truth table becomes Table 2. Try to derive tests to detect the fault (faults).

		AB			
		00	01	11	10
CD	00	1			
	01		1	1	
	11				1
	10			1	1

Table 1

		AB			
		00	01	11	10
CD	00				
	01		1	1	
	11				
	10	1		1	1

Table 2

**Solution:** Compare two truth tables, we can tell the circuit has stuck-at-0 fault at output when input (A, B, C, D) equals (0, 0, 0, 0) or (1, 0, 1, 1). The circuit also has stuck-at-1 fault at output when the input equals (0, 0, 1, 0).

**Answers:** {(0, 0, 0, 0), (1, 0, 1, 1), (0, 0, 1, 0)}

2. (80%) Generate a test for the fault f-sa1 in Figure 1 by the following FOUR methods. Be sure to give the **key steps to show the features of every algorithm**, and also **draw the decision trees** for each case.

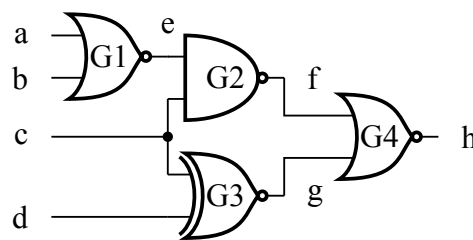


Figure 1

- (a) (20%) Use the **Boolean difference method** to derive all the test patterns to detect the fault f-sa1.

**Solution:** To test the stuck-at-1 fault at  $f$ ,  $f$  must equal 0 to activate the fault. In addition, the fault has to be observable at the output, meaning that the boolean difference of the logic function  $F$  w.r.t.  $f$  should be 1, i.e.,  $F_f(0) \oplus F_f(1) = 1$ .

$$\begin{aligned}
f &= 0 \\
f' &= 1 \\
F_f(0) \oplus F_f(1) &= 1 \\
(f')(F_f(0) \oplus F_f(1)) &= 1 \\
(f')(0 + (c \oplus d)')' \oplus (1 + (c \oplus d)')' &= 1 \\
(f')(c \oplus d \oplus 0) &= 1 \\
(f')(c \oplus d) &= 1 \\
((a + b)'c)''(c \oplus d) &= 1 \\
((a + b)'c)(c \oplus d) &= 1 \\
a'b'c(c \oplus d) &= 1 \\
a'b'c(cd' + c'd) &= 1 \\
a'b'ccd' + a'b'cc'd &= 1 \\
a'b'cd' &= 1
\end{aligned}$$

**Answer:**  $\{(a, b, c, d) \mid a'b'cd' = 1\} = \{(0, 0, 1, 0)\}.$

(b) (20%) Generate a test for the fault f-sa1 by using **D-algorithm**.

**Solution:** We'll use some acronyms, explained in Table 3, in the following D-algorithm procedure, shown in Table 4.

Acronym	Meaning	Comments
TC	Test Cube	TC(n) is the test cube at APTG step n.
PDCF	Primitive D-Cube for a Fault	Minimal input condition to activate the fault.
PDC	Propagation D-Cube	Minimal input condition to propagate the fault through a gate.
SC	Single Cover	Valid input/output combination for a gate.

Table 3: Acronym for D-algorithm procedure

Step	Comments	Cube							
		a	b	c	d	e	f	g	h
1	Activate f-sa1. $TC(0) = PDCF$			1		1	D'		
2	Backward implication: $SC_{G1}$ $TC(1) = TC(0) \cap SC_{G1}$	<b>0</b> 0	<b>0</b> 0			1 1			
3	Propagate fault. D-drive = G4. $PDC_{G4}$ $TC(2) = TC(1) \cap PDC_{G4}$	0	0	1		1	D' D'	0 0	D D
4	Backward implication: $SC_{G3}$ $TC(3) = TC(2) \cap SC_{G3}$	0	0	1	<b>0</b> 0			0 0	
5	No justification needed. Test generated, $(a, b, c, d) = (0, 0, 1, 0)$								

Table 4: The procedure for D-algorithm

**Answer:**  $(a, b, c, d) = (0, 0, 1, 0)$ .

(c) (20%) Generate a test for the fault f-sa1 by using **9-V Algorithm**.

**Solution:** The acronyms in Problem 2(b) are also used in the 9-V algorithm procedure, shown in Table 5.

Step	Comments	Cube							
		a	b	c	d	e	f	g	h
1	Activate f-sa1. $TC(0) = PDCF$			1		1	D'		
2	Backward implication: $SC_{G1}$ Forward implication: $SC_{G4}$ $TC(1) = TC(0) \cap SC_{G1} \cap SC_{G4}$	<b>0</b> 0	<b>0</b> 0			1 1			
3	Propagate fault. D-drive = G4. $PDC_{G4}$ $TC(2) = TC(1) \cap PDC_{G4}$	0	0	1		1	D' D'	0 0	D D
4	Backward implication: $SC_{G3}$ $TC(3) = TC(2) \cap SC_{G3}$	0	0	1	<b>0</b> 0			0 0	
5	No justification needed. Test generated, $(a, b, c, d) = (0, 0, 1, 0)$								

Table 5: The procedure for 9-V algorithm

**Answer:**  $(a, b, c, d) = (0, 0, 1, 0)$ .

(d) (20%) Generate a test for the fault f-sa1 by using **PODEM algorithm**.

**Solution:**

1. Activate f-sa1. Initial objective:  $f = 0$ .
2. Since G2 is an imply gate, backtrace to the hardest PI, a. With an even inversion parity,  $a = 0$ . Simulation, objective not achieved.

3. Backtrace to the next hardest PI, b. With an even inversion parity,  $b = 0$ ,  $e = 1$ . Simulation, objective not achieved.
4. Backtrace to the next hardest PI, c. With an odd inversion parity,  $c = 1$ . Simulation, objective achieved.
5. Propagate the fault. Objective:  $g = 0$ .
6. Backtrace to the remaining PI, d. With an odd inversion parity,  $d = 1$ . Simulation,  $g = (c \oplus d)' = 0$ . Conflict with the objective. Flip d to 0. Simulation, objective achieved.
7. Test generated,  $(a, b, c, d) = (0, 0, 1, 0)$ .

**Answer:**  $(a, b, c, d) = (0, 0, 1, 0)$ .